

### **Clean Copy of Claims**

The following is a clean copy of amended claims 1 and 8.

1     1. An integrated circuit including an embedded memory and a built-in self-test arrangement  
2     including  
3         means for storing test instruction including means for discriminating a source of a test  
4     command for performing manufacturing level and board level testing and receiving test  
5     instructions provided from an external tester,  
6         means for generating default test instructions, and  
7         means for supplying said default test instructions to said means for storing test  
8     instructions.

1     8. An electronic system including an integrated circuit having a built-in self-test arrangement  
2     therein, said integrated circuit including  
3         means for storing test instructions including means for discriminating a source of a test  
4     command for performing manufacturing level and board level testing and receiving test  
5     instructions provided from an external tester,  
6         means for generating default test instructions in absence of instructions from an external  
7     tester, and  
8         means for supplying said default test instructions to said means for storing test  
9     instructions.